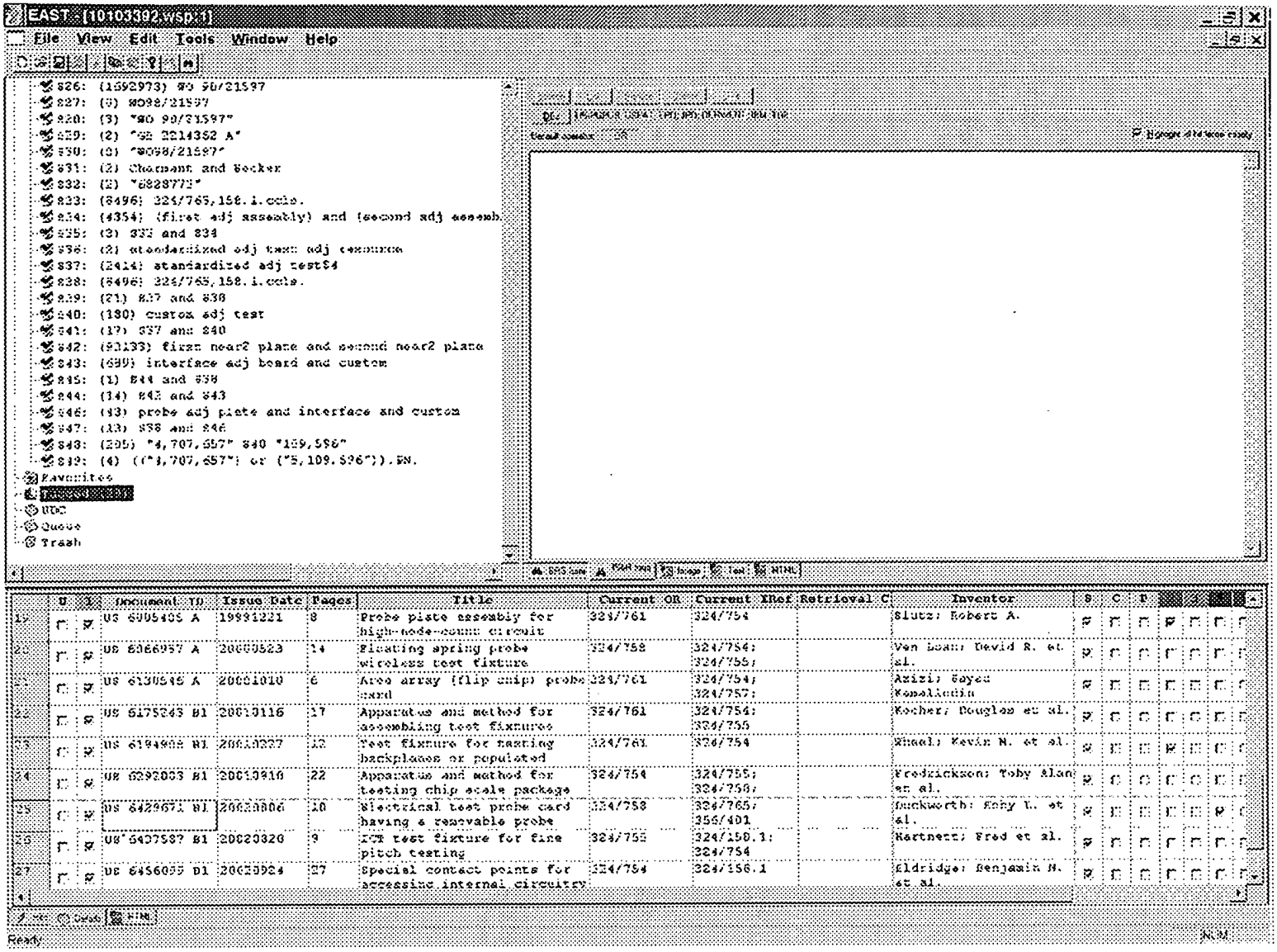
EAST - [10103392.wsp: 1]
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826: (1592973) WO 98/21597
827: (3) WO98/21597
828: (3) "WO 98/21597"
829: (2) "GB 2214352 A"
830: (3) "WO98/21597"
831: (2) Chapman and Becker
832: (2) "6828772"
833: (8496) 324/765,158.1.ccls.
834: (4354) (first adj assembly) and (second adj assemb
835: (3) 833 and 834
836: (2) standardized adj test adj consumer
837: (2414) standardized adj test$4
838: (8496) 324/765,158.1.ccls.
839: (21) 837 and 838
840: (180) custom adj test
841: (17) 837 and 840
842: (93133) first near2 plate and second near2 plate
843: (699) interface adj board and custom
845: (1) 844 and 838
844: (14) 843 and 843
846: (43) probe adj plate and interface and custom
847: (13) 838 and 846
848: (205) "4,707,657" 840 "159,596"
849: (4) (("4,707,657") or ("5,109,596")).PN.
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	U	S	Document ID	Issue Date	Pages	Title	Current OR	Current XRef	Retrieval C	Inventor	S	C	P				
19			US 6005405 A	19991221	8	Probe plate assembly for high-node-count circuit	324/761	324/754		Slutz; Robert A.							
20			US 6066957 A	20000523	14	Floating spring probe wireless test fixture	324/758	324/754; 324/755;		Van Loan; David R. et al.							
21			US 6130545 A	20001010	6	Area array (flip chip) probe card	324/761	324/754; 324/757;		Azizi; Sayed Kamaluddin							
22			US 6175243 B1	20010116	17	Apparatus and method for assembling test fixtures	324/761	324/754; 324/755		Kocher; Douglas et al.							
23			US 6184908 B1	20010207	12	Test fixture for testing backplanes or populated	324/761	324/754		Khaal; Kevin N. et al.							
24			US 6292003 B1	20010918	22	Apparatus and method for testing chip scale package	324/754	324/755; 324/758;		Fredrickson; Toby Alan et al.							
25			US 6429671 B1	20020806	10	Electrical test probe card having a removable probe	324/758	324/765; 356/401		Duckworth; Tony L. et al.							
26			US 6437587 B1	20020820	9	PCB test fixture for fine pitch testing	324/755	324/158.1; 324/754		Hartnett; Fred et al.							
27			US 6456099 B1	20020924	27	Special contact points for accessing internal circuitry	324/754	324/158.1		Eldridge; Benjamin N. et al.							

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